

## LMN3612PJZF 30V N-Channel MOSFET

### Features

- 30V, 5.3A,  $R_{DS(ON)}=36m\Omega@V_{GS}=4.5V$
- Improved dv/dt capability
- Fast switching
- Suit for 2.5V Gate Drive Applications
- Green Device Available
- SOT-23 package design

### Product Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has

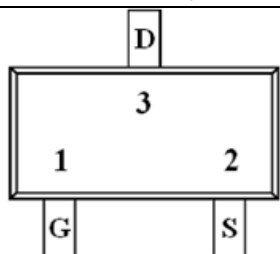
been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

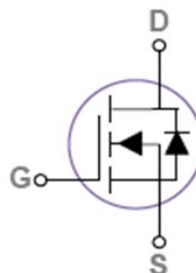
These devices are well suited for high efficiency fast switching applications.

### Applications

- Notebook
- Load Switch
- LED applications

### Pin Configuration

LMN3612PJZF (SOT-23)	
 <p>Transparent top view</p>	
Pin	Description
1	Gate
2	Source
3	Drain



**Ordering Information**

Ordering Information					
Part Number	P/N	PKG code	Pb Free code	Package	Quantity
LMN3612PJZF	LMN3612P	JZ	F	SOT-23	3000 PCS

**Marking Information**

Marking Information		
Part Marking	Part Number	LFC code
PXWMM	P	XWMM

**Absolute Maximum Ratings**

(T<sub>C</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Typical	Unit
V <sub>DSS</sub>	Drain-Source Voltage	30	V
V <sub>GSS</sub>	Gate-Source Voltage	±12	V
I <sub>D</sub>	Continuous Drain Current	T <sub>A</sub> =25°C	A
		T <sub>C</sub> =100°C	
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	21.2	A
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> =25°C)	1.56	W
	Power Dissipation (Derate above 25°C)	0.012	
T <sub>J</sub>	Operating Junction Temperature	-55 to +150	°C
T <sub>STG</sub>	Storage Temperature Range	-55 to +150	°C
R <sub>θJA</sub>	Thermal Resistance-Junction to Ambient <sup>1</sup>	80	°C/W

**Electrical Characteristics**

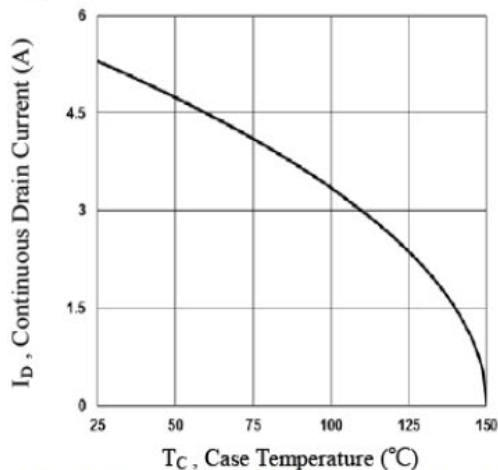
(T<sub>C</sub>=25°C Unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30			V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA		0.06		V/°C
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	0.4	0.6	0.9	V
ΔV <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient			-3		mV/°C
I <sub>GSS</sub>	Gate Leakage Current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±12V			±100	nA
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1	uA
		V <sub>DS</sub> =24V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			10	
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V, Force Current			5.3	A
I <sub>SM</sub>	Pulsed Source Current				21.2	
R <sub>DS(on)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A		31	36	mΩ
		V <sub>GS</sub> =2.5V, I <sub>D</sub> =3A		36	45	
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> =3A		7		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			1	V
Dynamic						
Q <sub>g</sub>	Total Gate Charge <sup>2,3</sup>	V <sub>DS</sub> =10V, V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A		8.4	12	nC
Q <sub>gs</sub>	Gate-Source Charge <sup>2,3</sup>			1	2	
Q <sub>gd</sub>	Gate-Drain Charge <sup>2,3</sup>			2.2	4	
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =10V, V <sub>GS</sub> =0V, f=1MHz		695	1000	pF
C <sub>oss</sub>	Output Capacitance			45	65	
C <sub>rss</sub>	Reverse Transfer Capacitance			36	50	
t <sub>d(on)</sub>	Turn-On Time <sup>2,3</sup>	V <sub>DD</sub> =10V, I <sub>D</sub> =1A, V <sub>GS</sub> =4.5V, R <sub>G</sub> =25Ω		4.5	9	ns
t <sub>r</sub>				13	25	
t <sub>d(off)</sub>	Turn-Off Time <sup>2,3</sup>			27	51	
t <sub>f</sub>				8.3	16	
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz		1.5	3	Ω

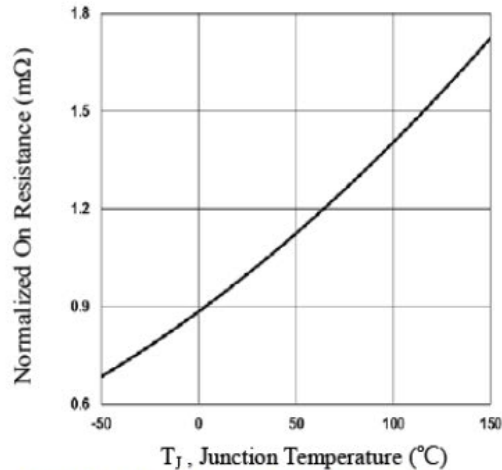
Note:

1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≤300us , duty cycle ≤2%.
3. Essentially independent of operating temperature.

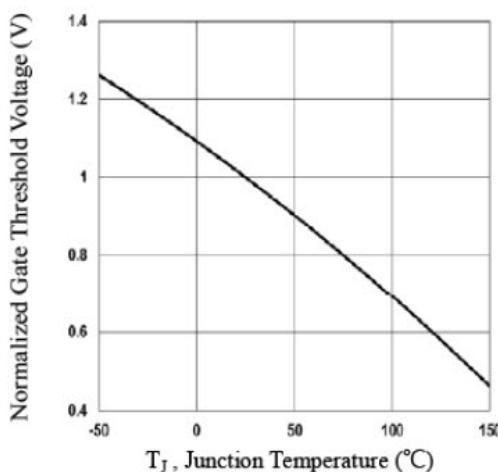
# Typical Performance Characteristics



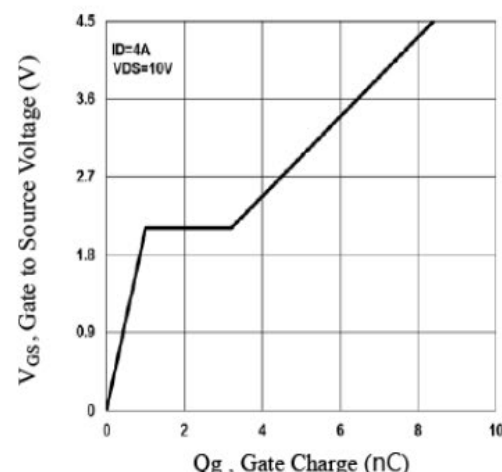
**Fig.1 Continuous Drain Current vs.  $T_C$**



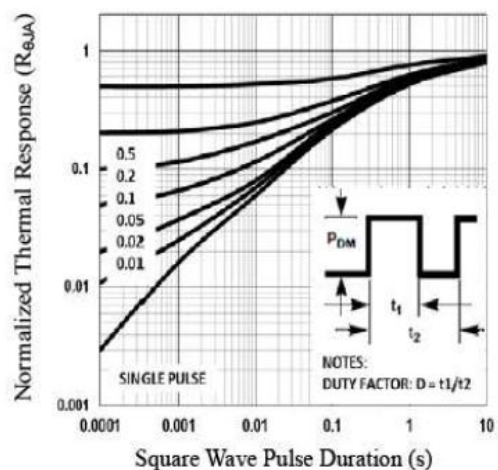
**Fig.2 Normalized  $R_{DS(on)}$  vs.  $T_J$**



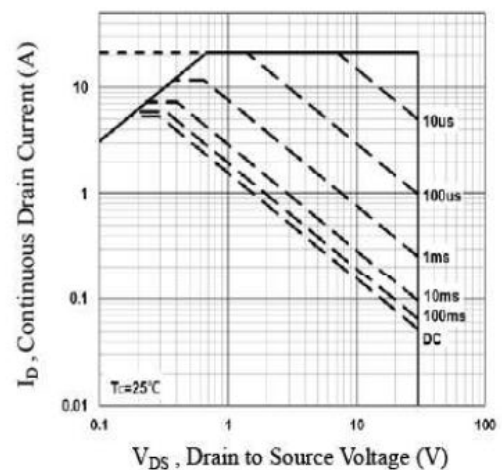
**Fig.3 Normalized  $V_{th}$  vs.  $T_J$**



**Fig.4 Gate Charge Waveform**



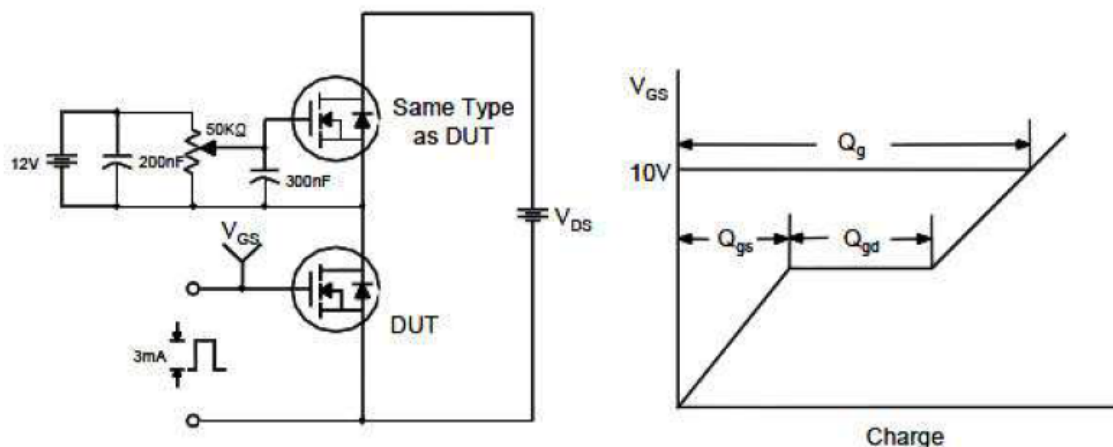
**Fig.5 Normalized Transient Impedance**



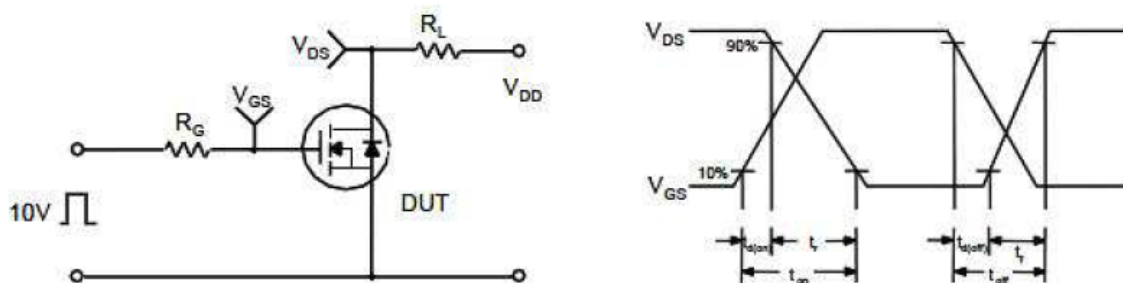
**Fig.6 Maximum Safe Operation Area**

# Typical Performance Characteristics(continue)

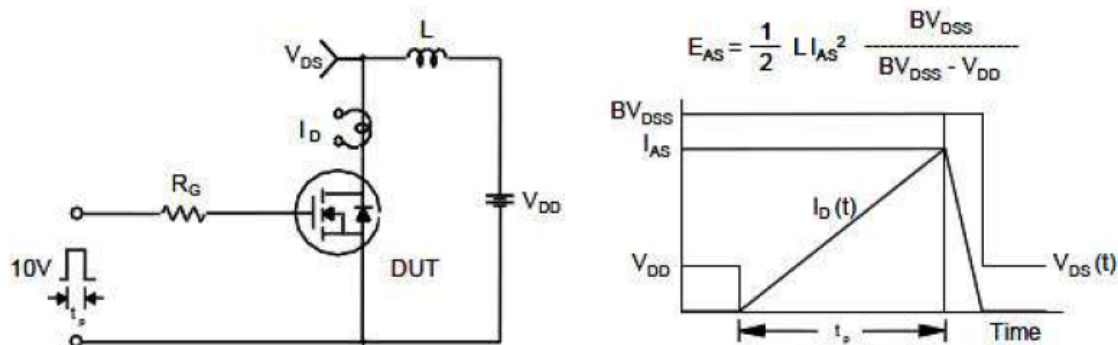
Gate Charge Test Circuit &amp; Waveform

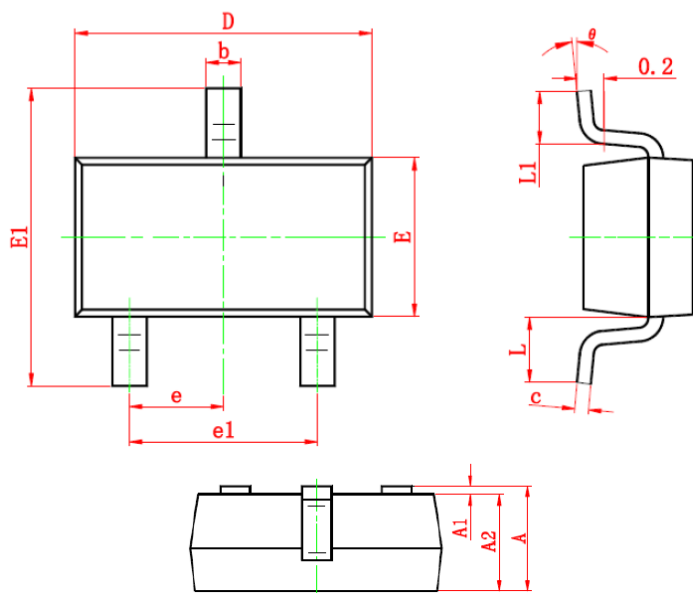


Resistive Switching Test Circuit &amp; Waveforms



Unclamped Inductive Switching Test Circuit &amp; Waveforms



**Package Dimension:**
**SOT-23**


Dimensions				
Symbol	Millimeters		Inches	
	Min	Max	Min	Max
<b>A</b>	0.90	1.20	0.035	0.043
<b>A1</b>	0.00	0.10	0.000	0.004
<b>A2</b>	0.90	1.10	0.035	0.039
<b>b</b>	0.30	0.50	0.012	0.020
<b>c</b>	0.08	0.15	0.003	0.006
<b>D</b>	2.80	3.00	0.110	0.118
<b>E</b>	1.20	1.40	0.047	0.055
<b>E1</b>	2.25	2.55	0.089	0.10
<b>e</b>	0.95 TYP		0.037 TYP	
<b>e1</b>	1.80	2.00	0.071	0.079
<b>L</b>	0.55 REF		0.022 REF	
<b>L1</b>	0.30	0.50	0.012	0.020
<b>θ</b>	0°	8°	0°	8°

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